

- 10:30 F-74 *Invited*—Analysis of Indoor Fine Dust**
U.E.A. Fittschen, A. Rehmers, *University of Hamburg, Hamburg, Germany*
M. Santen, *Greenpeace Hamburg, Hamburg, Germany*
M. Wesselmann, *Bauinstitut Hamburg, Hamburg, Germany*
- 11:00 F-62 Characterization of Nanoparticles with X-ray Spectrometry under Grazing Incidence Conditions**
F. Reinhardt, B. Beckhoff, B. Pollakowski, *Physikalisch-Technische Bundesanstalt, Berlin, Germany*
H. Bresch, S. Seeger, *Bundesanstalt für Materialforschung und –prüfung, Berlin, Germany*
- 11:20 F-65 Assessment of Advanced X-ray GIXRF Methodology Applied to the Characterization of Ultra Shallow Junctions**
P. Hönicke, B. Beckhoff, M. Kolbe, *Physikalisch-Technische Bundesanstalt, Berlin, Germany*
D. Giuberton, G. Pepponi, *Fondazione Bruno Kessler, Trento, Italy*
J. van den Berg, *University of Salford, Salford, UK*
- 11:40 F-49 Comparison of X-ray and Mass Spectroscopy Based Analytical Methods for Detection of Organic Contamination**
A. Nutsch, A. Leibold, L. Pfitzner, M. Otto, *Fraunhofer IISB, Erlangen, Germany*
B. Beckhoff, M. Müller, *Physikalisch-Technische Bundesanstalt, Berlin, Germany*
G. Bedana, G. Borionetti, G. Guerinoni, *MEMC Electronic Materials SpA, Novara, Italy*
M.-L. Polignano, D. Codegoni, S. Grasso, D. De Simone, *Numonyx, Milan, Italy*